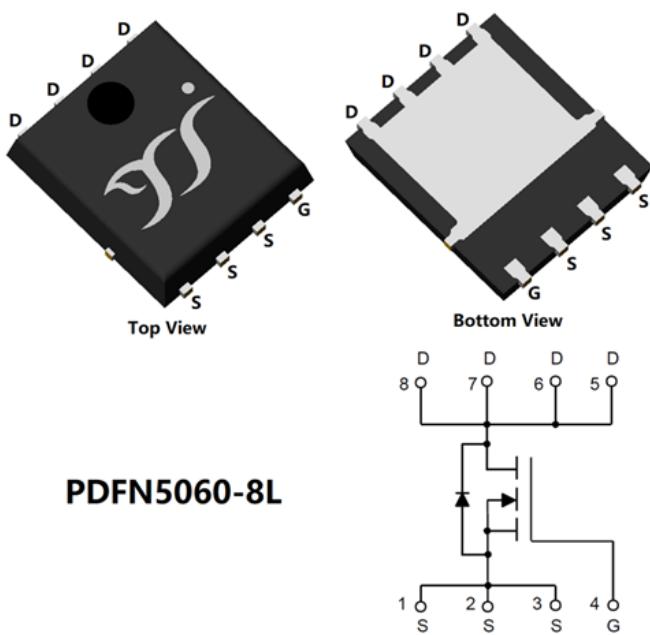




N-Channel Enhancement Mode Field Effect Transistor



Product Summary

- V_{DS} 30V
- I_D 105A
- $R_{DS(ON)}$ ($V_{GS} = 10V$) $<3.0\text{mohm}$
- $R_{DS(ON)}$ ($V_{GS} = 4.5V$) $<4.0\text{mohm}$
- 100% EAS Tested
- 100% ∇V_{DS} Tested

General Description

- Trench Power MV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$
- Moisture Sensitivity Level 1
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

Applications

- DC-DC Converters
- Power management functions
- Backlighting

■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		V_{DS}	30	V
Gate-source Voltage		V_{GS}	± 20	V
Drain Current	$T_c=25^\circ\text{C}$	I_D	105	A
	$T_c=100^\circ\text{C}$		66	
Pulsed Drain Current ^A		I_{DM}	415	A
Total Power Dissipation @ $T_c=25^\circ\text{C}$		P_D	70	W
Single Pulse Avalanche Energy ^B		E_{AS}	507	mJ
Thermal Resistance Junction-to-Case		$R_{\theta JC}$	1.8	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction-to-Ambient		$R_{\theta JA}$	50	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range		T_J, T_{STG}	-55~+150	$^\circ\text{C}$

■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJG105N03A	F1	YJG105N03A	5000	10000	100000	13" reel



YJG105N03A

■ Electrical Characteristics ($T_J=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	I_{DSSS}	$V_{DS}=30V, V_{GS}=0V$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.5	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$		2.45	3.0	$m\Omega$
		$V_{GS}=4.5V, I_D=15A$		2.9	4.0	
Diode Forward Voltage	V_{SD}	$I_S=20A, V_{GS}=0V$		0.85	1.2	V
Gate resistance	R_G	$f=1MHz$	-	1.5	-	Ω
Maximum Body-Diode Continuous Current	I_S				105	A
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{DS}=15V, V_{GS}=0V, f=1MHz$		4401		pF
Output Capacitance	C_{oss}			581		
Reverse Transfer Capacitance	C_{rss}			439		
Switching Parameters						
Total Gate Charge	Q_g	$V_{GS}=10V, V_{DS}=20V, I_D=20A$		49.5		nC
Gate-Source Charge	Q_{gs}			10.4		
Gate-Drain Charge	Q_{gd}			8.9		
Reverse Recovery Charge	Q_{rr}	$I_F=20A, di/dt=500A/us$		7.5		ns
Reverse Recovery Time	t_{rr}			23		
Turn-on Delay Time	$t_{D(on)}$			13		
Turn-on Rise Time	t_r	$V_{GS}=10V, V_{DD}=15V, I_D=2A, R_{GEN}=3\Omega$		22		
Turn-off Delay Time	$t_{D(off)}$			63		
Turn-off fall Time	t_f			33		

A. Pulse Test: Pulse Width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

B. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

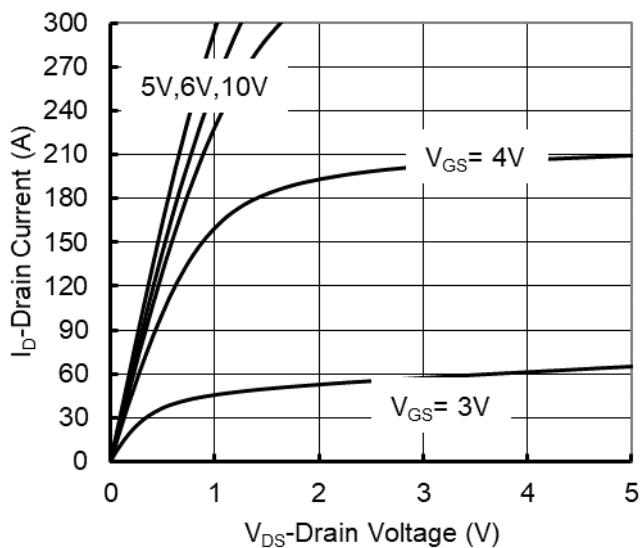
**■ Typical Performance Characteristics**

Figure 1. Output Characteristics

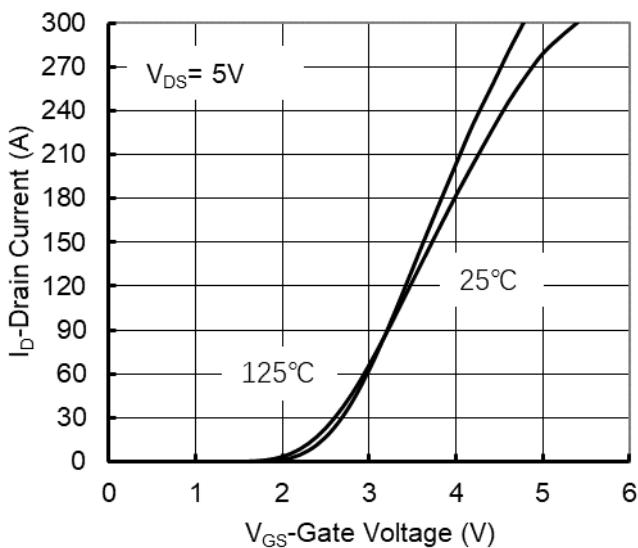


Figure 2. Transfer Characteristics

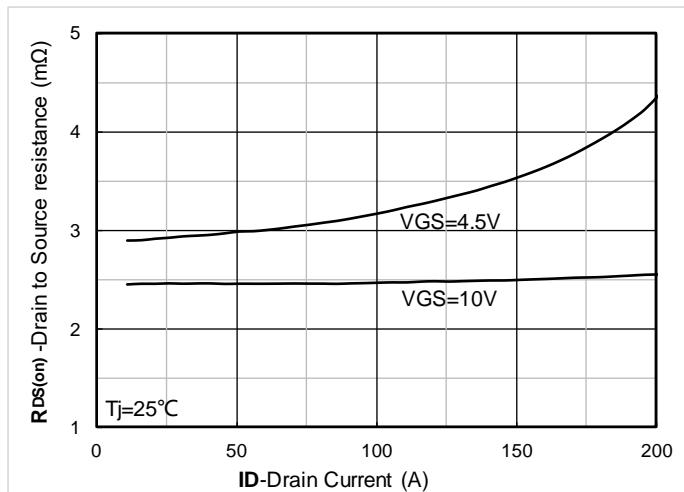


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

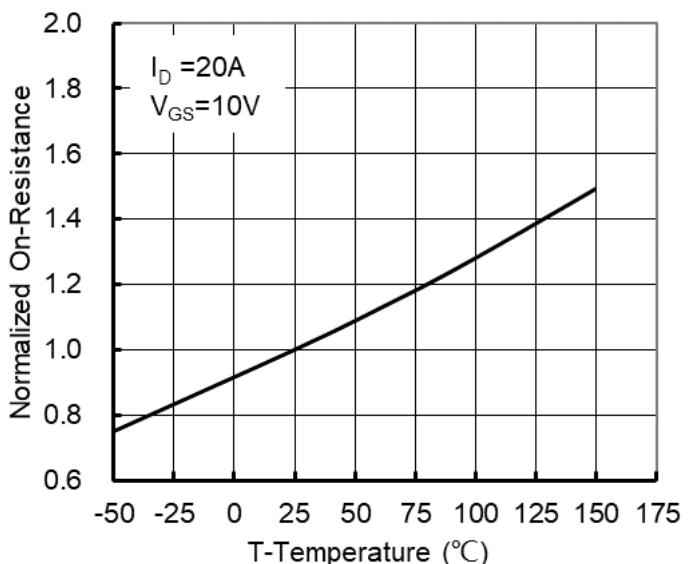


Figure 4. On-Resistance vs. Junction Temperature

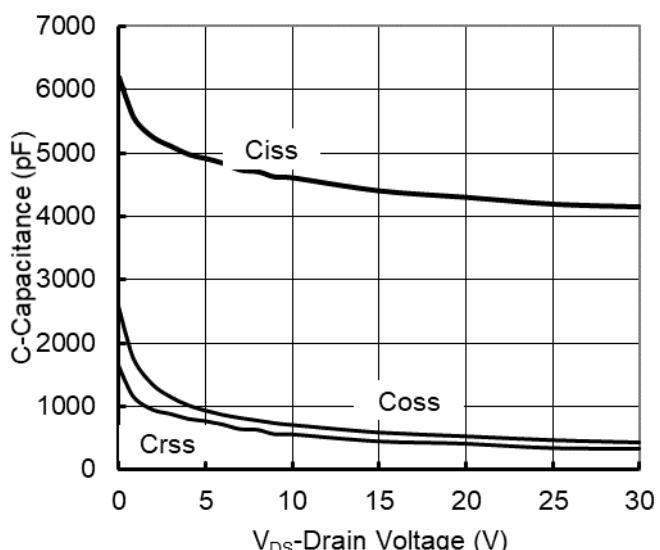


Figure 5. Capacitance Characteristics

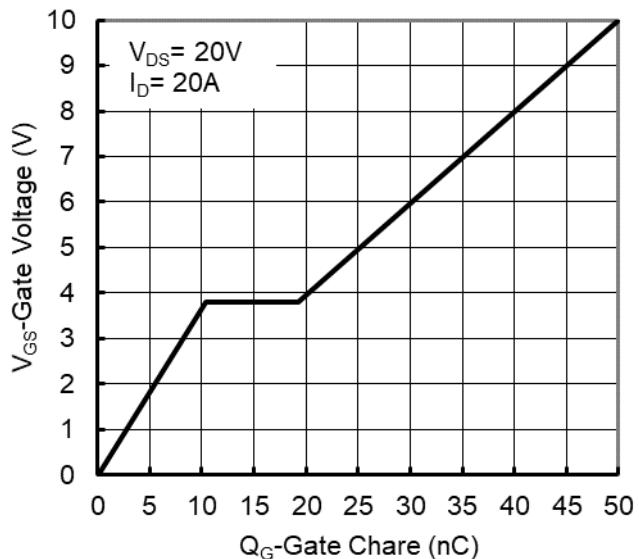


Figure 6. Gate Charge

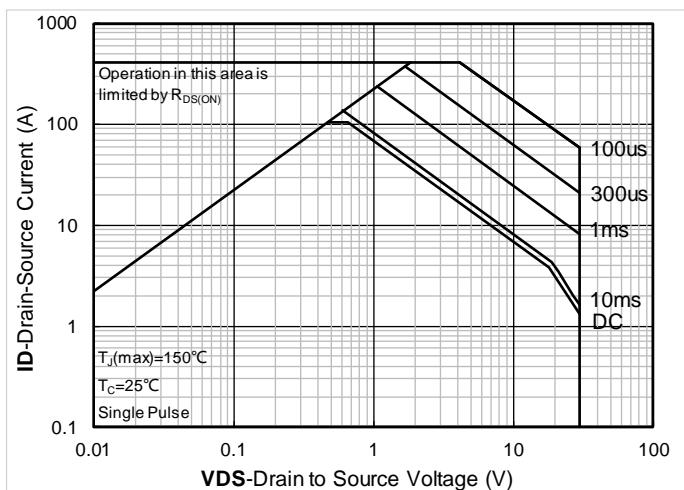


Figure 7. Safe Operation Area

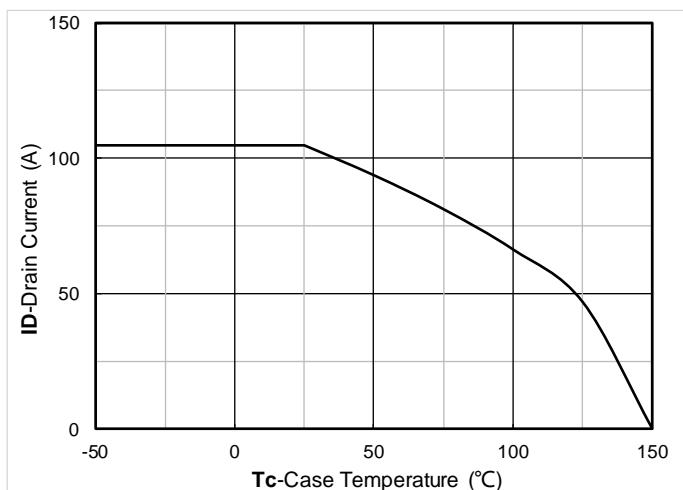


Figure 8. Maximum Continuous Drain Current vs Case Temperature

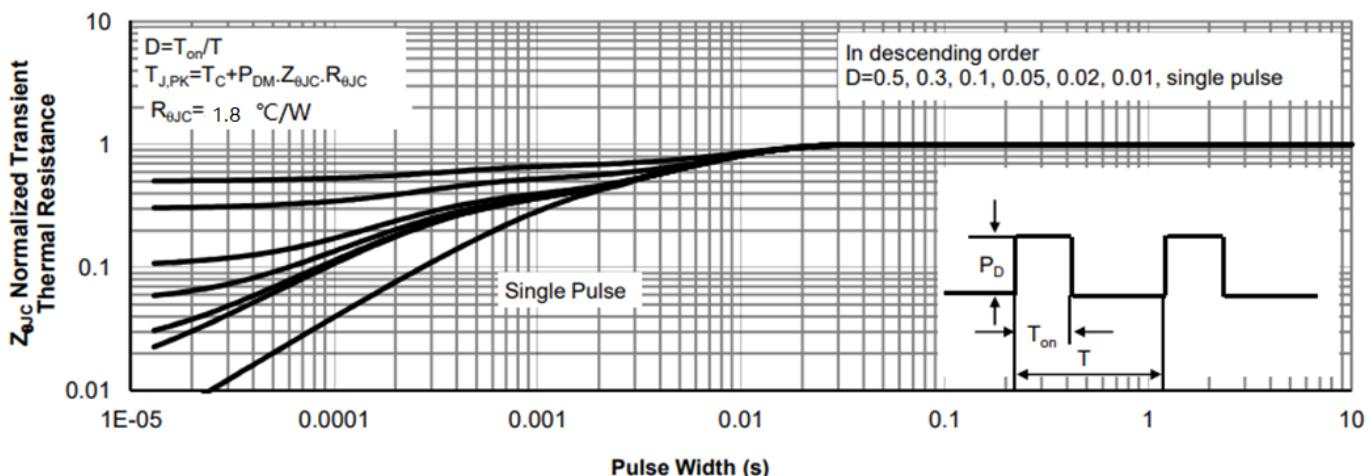
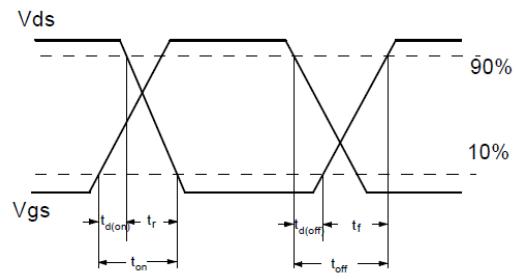
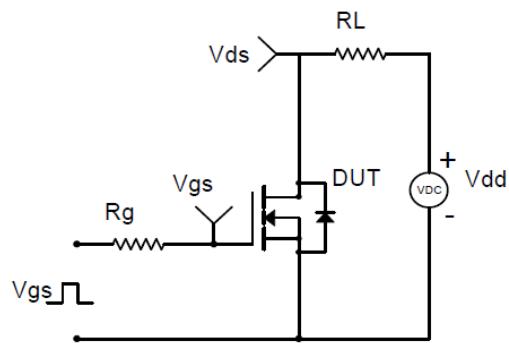
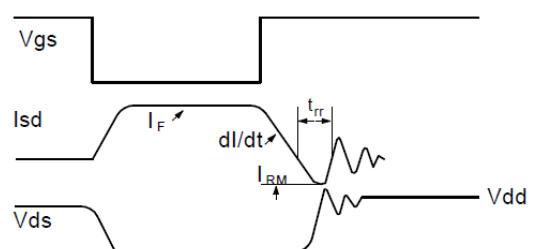
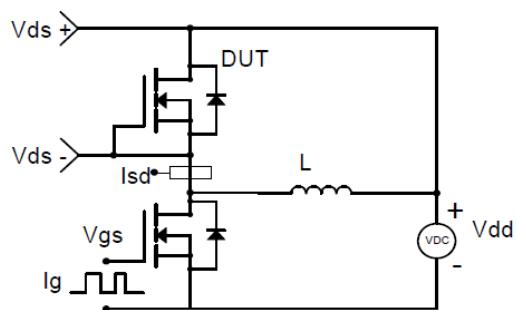


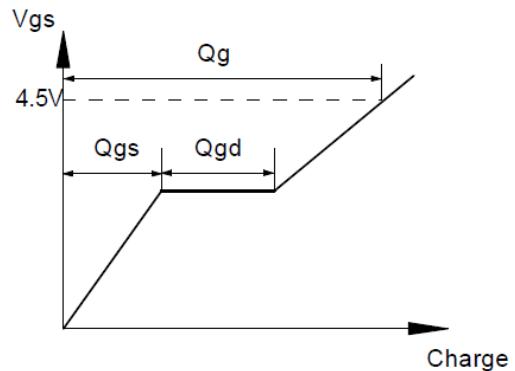
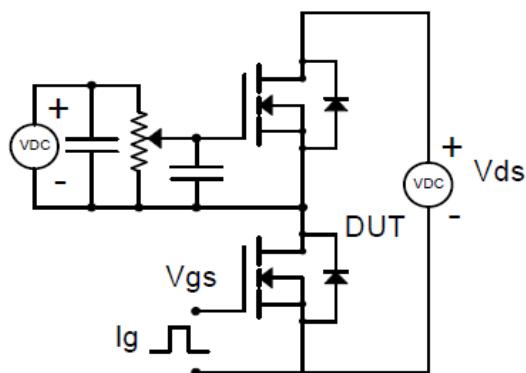
Figure 9. Normalized Maximum Transient Thermal Impedance



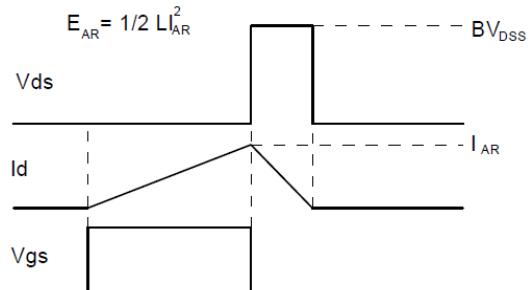
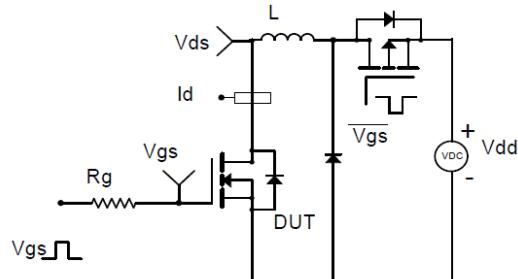
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



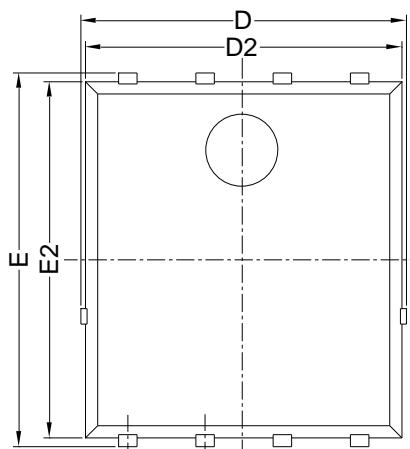
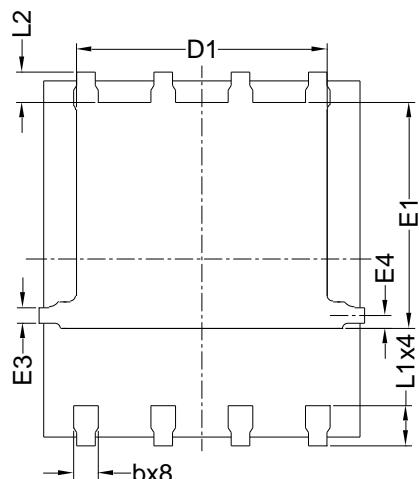
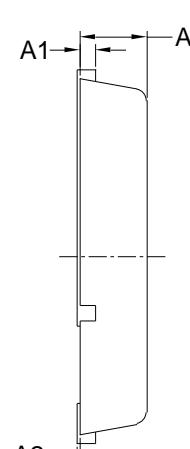
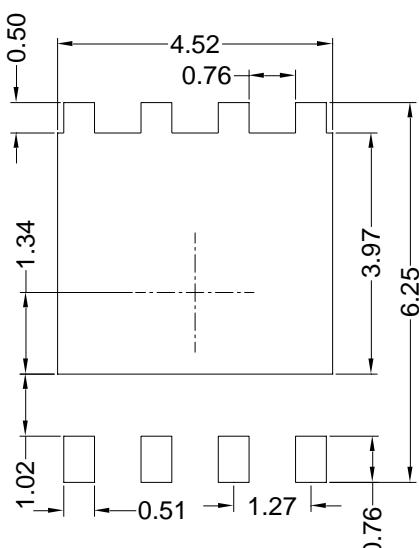
Gate Charge Test Circuit & Waveform



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



■ PDFN5060-8L-B-1.1MM Package Information

Top View
正面视图Bottom View
背面视图Side View
侧面视图Suggested Solder Pad Layout
Top View

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	5.15	5.35	5.55
E	5.95	6.15	6.35
A	1.00	1.10	1.20
A1	0.254	BSC	
A2			0.10
D1	3.92	4.12	4.32
E1	3.52	3.72	3.92
D2	5.00	5.20	5.40
E2	5.66	5.86	6.06
E3	0.254	REF	
E4	0.21	REF	
L1	0.56	0.66	0.76
L2		0.50	BSC
b	0.31	0.41	0.51
e		1.27	BSC

Note:

1. Controlling dimension:in millimeters.
2. General tolerance: $\pm 0.10\text{mm}$.
3. The pad layout is for reference purposes only.



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